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Session Chair: *Robert Pennington (Robins AFB)*

Panel Session

In November 2007, the US Air Force declared the Versatile Depot Automatic Test System (VDATS) to be the preferred system solution from the DoD family of approved testers. In addition, the Air Force chartered the ATS Division at Robins AFB to implement the system as an enterprise-level automatic test system. To date, implementation of that directive has progressed within the confines of mission needs and budgetary requirements. This panel will seek to clarify the short-term and long-term direction of VDATS implementation.

Panel Members:

- Kevin Simpson
- Joe Eckersley
- Larry Adams
- John Stabler

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Session Chair: *Dr. Michael N. Granieri (Phase Matrix, Inc.)*

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The technology of Synthetic Instrumentation has been undergoing a steady maturation process over the past decade. This panel session will focus on the current state of the technology and a prognosis by expert panelists on the “road ahead” for this most interesting technology.

Panelists:

- *Larry Adams (USAF, WRALC)*
- *David R. Carey (US Army, Tobyhanna)*
- *Kevin Dusch (NAVAIR PMA 260)*
- *Tim Fountain (National Instruments)*
- *Matt Hunter (ZTEC Instruments)*
- *Wade Lowdermilk (BAE Systems)*
- *Les Orlidge (AAI Corp/Textron Systems)*
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Panel Session

The ATML Panel will be a collection of ATML users who have been responsible for specifying and using the ATML standards on current fielded systems. The panelists will represent a wide range of military and commercial programs using ATML and provide an overview of their experiences, describing how ATML was used on their projects and highlighting the advantages/disadvantages their teams ran across plus any lessons learned which may be of interest to others doing a similar activity. There will be an opportunity for Q&A from the audience.

Panelists:

- *Mike Seavey (Northrop Grumman & SCC20 Chair)*
- *Tony Alwardt (The Boeing Company)*
- *Michelle Harris (Lockheed Martin)*
- *Brit Frank (US Army)*
- *Anand Jain (National Instruments)*
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